

<IGBT Modules>

# CM200DY-24TH

HIGH POWER SWITCHING USE INSULATED TYPE



- •Copper base plate (Nickel-plating)
- •Tin-plating tab terminals
- RoHS Directive compliant
- •UL Recognized under UL1557, File No. E323585

Dimension in mm

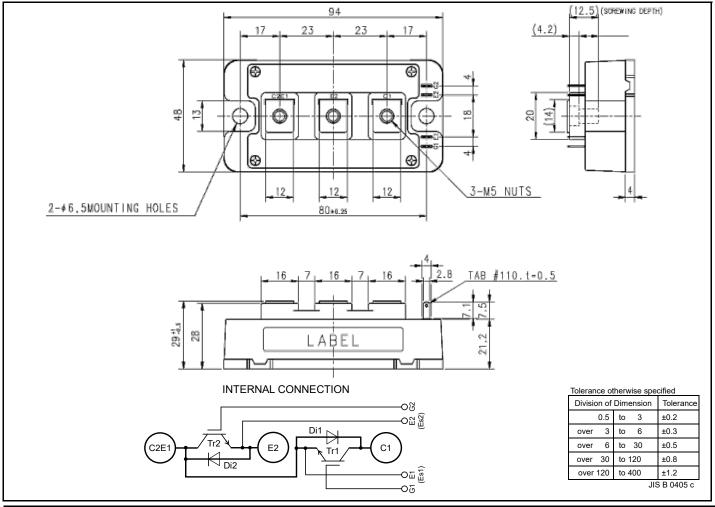
#### APPLICATION

Medical equipment, Welder, Power supply, etc.

**OPTION (Below options are available.)** 

•VcEsat selection for parallel connection

#### **OUTLINE DRAWING & INTERNAL CONNECTION**



Publication Date : December 2020

# MITSUBISHI ELECTRIC CORPORATION

Symbol	Item	Conditions	Rating	Unit
V <sub>CES</sub>	Collector-emitter voltage	G-E short-circuited	1200	V
V <sub>GES</sub>	Gate-emitter voltage	C-E short-circuited	± 20	V
Ic	DC, T <sub>C</sub> =25 °C (Note2, 4)		200	^
I <sub>CRM</sub>	Collector current	Pulse, Repetitive (Note3)	400	A
Ptot	Total power dissipation	T <sub>C</sub> =25 °C (Note2, 4)	970	W
IE (Note1)		DC, T <sub>C</sub> =25 °C (Note2)	200	٨
IERM (Note1)	Emitter current	Pulse, Repetitive (Note3)	400	A
Visol	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V
T <sub>vjmax</sub>	Maximum junction temperature	Instantaneous event (overload) (Note 8)	175	°C
T <sub>Cmax</sub>	Maximum case temperature	(Note4, 8)	125	
Tvjop	Operating junction temperature	Continuous operation (under switching) <sup>(Note 8)</sup>	-40 ~ +150	°C
Tstg	Storage temperature	-	-40 ~ +125	

#### MAXIMUM RATINGS ( $T_{vj}$ =25 °C, unless otherwise specified)

## ELECTRICAL CHARACTERISTICS (Tvj=25 °C, unless otherwise specified)

Symbol	Itom	Item Conditions		Limits			Linit
Symbol	liem			Min.	Тур.	Max.	Unit
I <sub>CES</sub>	Collector-emitter cut-off current		T <sub>vj</sub> =25 °C	-	-	1.0	mA
		V <sub>CE</sub> =V <sub>CES</sub> , G-E short-circuited	T <sub>vj</sub> =150 °C			50.0	mA
I <sub>GES</sub>	Gate-emitter leakage current	V <sub>GE</sub> =V <sub>GES</sub> , C-E short-circuited		-	-	0.5	μA
$V_{\text{GE(th)}}$	Gate-emitter threshold voltage	Ic=20 mA, V <sub>CE</sub> =10 V		5.40	6.00	6.60	V
.,		I <sub>C</sub> =200 A, V <sub>GE</sub> =15 V,	T <sub>vj</sub> =25 °C	-	4.45	5.15	V
V <sub>CEsat</sub> (Terminal)		Refer to the figure of test circuit	T <sub>vj</sub> =125 °C	-	4.55	-	
(Terriniar)	Collector omitter acturation valtage	(Note5)	T <sub>vj</sub> =150 °C	-	4.45	-	
	Collector-emitter saturation voltage	Ic=200 A,	T <sub>vj</sub> =25 °C	-	4.35	5.05	v
V <sub>CEsat</sub>		V <sub>GE</sub> =15 V,	T <sub>vj</sub> =125 °C	-	4.45	-	
(Chip)		(Note5)	T <sub>vj</sub> =150 °C	-	4.35	-	
Cies	Input capacitance			-	-	30.0	
Coes	Output capacitance	V <sub>CE</sub> =10 V, G-E short-circuited	V <sub>CE</sub> =10 V, G-E short-circuited		-	2.5	nF
Cres	Reverse transfer capacitance		-	-	0.5		
Q <sub>G</sub>	Gate charge	V <sub>CC</sub> =600 V, I <sub>C</sub> =200 A, V <sub>GE</sub> =15 V		-	0.5	-	μC
t <sub>d(on)</sub>	Turn-on delay time	$V_{CC}{=}600$ V, $I_{C}{=}200$ A, $V_{GE}{=}{\pm}15$ V, $R_{G}{=}0$ Ω, Inductive load		-	-	300	- ns
tr	Rise time			-	-	80	
$t_{d(off)}$	Turn-off delay time			-	-	500	
t <sub>f</sub>	Fall time			-	-	100	
(Nists ()	<b>F</b>	I <sub>E</sub> =200 A, G-E short-circuited,	T <sub>vj</sub> =25 °C	-	2.45	2.85	V
V <sub>EC</sub> <sup>(Note.1)</sup> (Terminal)		Refer to the figure of test circuit	T <sub>vj</sub> =125 °C	-	2.60	-	
(Terminal)		(Note5)	T <sub>vj</sub> =150 °C	-	2.55	-	
(Nists 4)	<ul> <li>Emitter-collector voltage</li> </ul>	I <sub>E</sub> =200 A,	T <sub>vj</sub> =25 °C	-	2.35	2.75	
V <sub>EC</sub> <sup>(Note.1)</sup> (Chip)		G-E short-circuited,	T <sub>vj</sub> =125 °C	-	2.50	-	V
(Chip)		(Note5)	T <sub>vj</sub> =150 °C	-	2.45	-	
t <sub>rr</sub> (Note1)	Reverse recovery time	V <sub>CC</sub> =600 V, I <sub>E</sub> =200 A, V <sub>GE</sub> =±15 V,		-	-	250	ns
Q <sub>rr</sub> (Note1)	Reverse recovery charge	$R_{G}=0 \Omega$ , Inductive load		-	13	-	μC
Eon	Turn-on switching energy per pulse	V <sub>CC</sub> =600 V, I <sub>C</sub> =I <sub>E</sub> =200 A,		-	5.0	-	
E <sub>off</sub>	Turn-off switching energy per pulse	$V_{GE}=\pm 15 \text{ V}, \text{ R}_{G}=0 \Omega, \text{ T}_{vj}=150 \text{ °C},$		-	10.0	-	mJ
Err (Note1)	Reverse recovery energy per pulse	Inductive load		-	10.0	-	mJ
R <sub>CC'+EE'</sub>	Internal lead resistance	Main terminals-chip, per switch, T <sub>C</sub> =25 °C (Note4)		-	0.4	-	mΩ
r <sub>g</sub>	Internal gate resistance	Per switch		-	1.6	-	Ω

#### THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions	Limits			Unit
	Item	Conditions	Min. Typ. Max.			
$R_{th(j-c)Q}$	Thermal resistance	Junction to case, per Inverter IGBT (Note4)	-	-	154	K/kW
$R_{th(j-c)D}$	Thermar resistance	Junction to case, per Inverter FWD (Note4)	-	-	284	r/kvv
$R_{th(c-s)}$	Contact thermal resistance	Case to heat sink, Thermal grease applied (Note4, 6, 8)	_	11	_	K/kW
		per 1 module,	-		-	

#### **MECHANICAL CHARACTERISTICS**

Symbol	Item	Conditions		Limits			Linit
	item			Min.	Тур.	Max.	Unit
Mt	Mounting torque	Main terminals	M 5 screw	2.5	3.0	3.5	N∙m
Ms	Mounting torque	Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N∙m
ds	Creepage distance	Terminal to terminal		17.0	-	-	mm
		Terminal to base plate		28.5	-	-	
da	Clearance	Terminal to terminal		11.0	-	-	22.22
	Clearance	Terminal to base plate		25.6	-	-	mm
ec	Flatness of base plate	On the centerline X ,Y (Note7)		-100	-	+100	μm
m	mass	-		-	310	-	g

\*. This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU and (EU)2015/863.

Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (FWD).

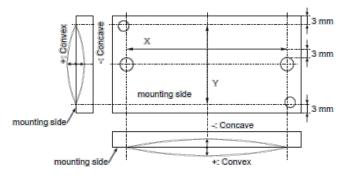
2. Junction temperature (T  $_{\nu j}$  ) should not increase beyond T  $_{\nu j\,m\,ax}$  rating.

3. Pulse width and repetition rate should be such that the device junction temperature  $(T_{vj})$  dose not exceed  $T_{vjmax}$  rating.

4. Case temperature (T<sub>c</sub>) and heat sink temperature (T<sub>s</sub>) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.

5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.

- 6. Typical value is measured by using thermally conductive grease of  $\lambda = 0.9 \text{ W/(m \cdot K)/D_{(C-S)}} = 100 \text{ µm}$ .
- 7. The base plate (mounting side) flatness measurement point (X,Y) is as follows of the following figure.



Long term performance related to thermal conductive grease and PC-TIM (including but not limited to aspects such as the increase of thermal resistance due to pumping out, etc.) should be verified under your specific application conditions. Each temperature condition (T<sub>vj max</sub>, T<sub>vj op</sub>, T<sub>C max</sub>) must be maintained below the maximum rated temperature throughout consideration of the temperature rise even for long term usage.

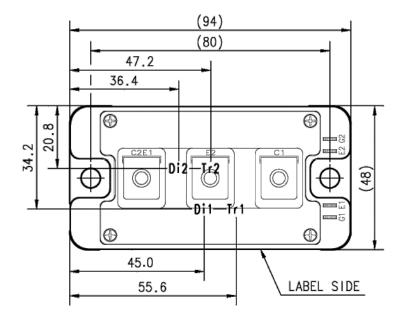
※ No short circuit capability is designed.

## **RECOMMENDED OPERATING CONDITIONS**

Symbol	ltom	Conditions	Limits			Linit
	Item	Conditions	Min.	Тур.	Max.	Unit
Vcc	(DC) Supply voltage	Applied across C1-E2 terminals	-	600	850	V
V <sub>GEon</sub>	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2 terminals	13.5	15.0	16.5	V
R <sub>G</sub>	External gate resistance	Per switch	0	-	10	Ω
f <sub>C</sub>	Switching frequency	V <sub>CC</sub> =600 V, R <sub>G</sub> =0 Ω, V <sub>GE</sub> =±15 V,T <sub>vj</sub> =150°C	-	-	60	kHz

#### CHIP LOCATION (Top view)

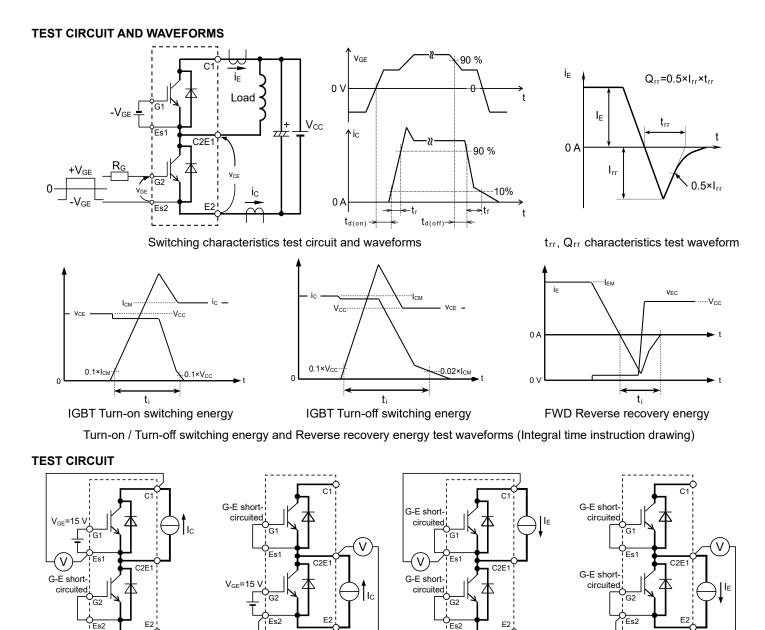
Dimension in mm, tolerance: ±1 mm



Tr1/Tr2: IGBT, Di1/Di2: FWD

4

## <IGBT Modules> CM200DY-24TH HIGH POWER SWITCHING USE INSULATED TYPE



VCEsat characteristics test circuit

Tr1

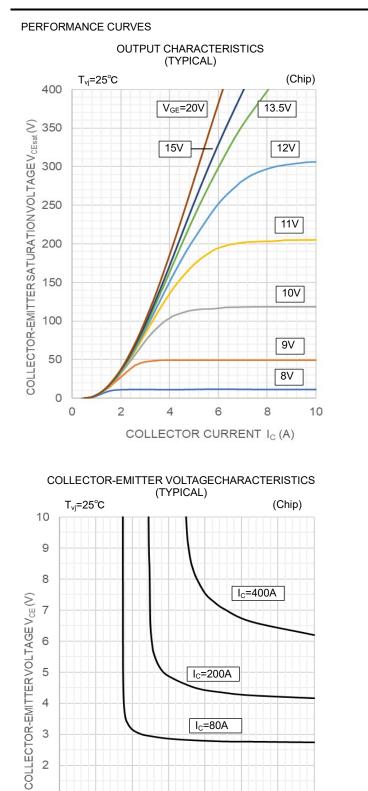
Di2

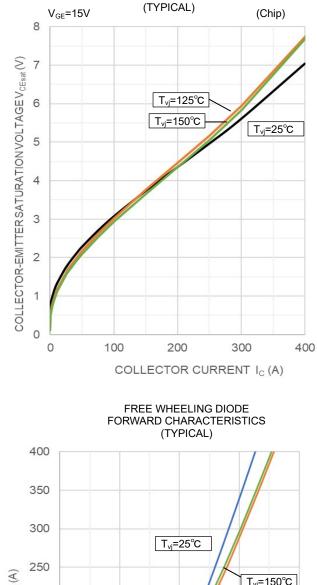
V<sub>EC</sub> characteristics test circuit

Di1

Tr2

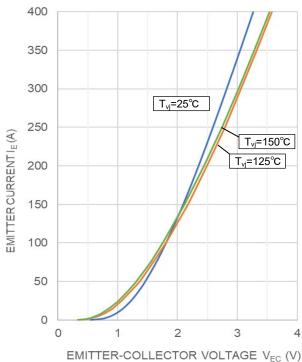
## <IGBT Modules> CM200DY-24TH HIGH POWER SWITCHING USE **INSULATED TYPE**





COLLECTOR-EMITTER SATURATION VOLTAGE

CHARACTERISTICS



10

12

GATE-EMITTER VOLTAGE VGE(V)

16

14

18

20

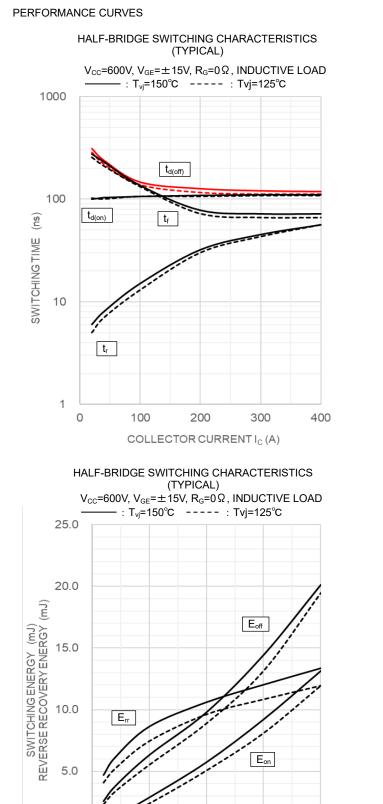
2

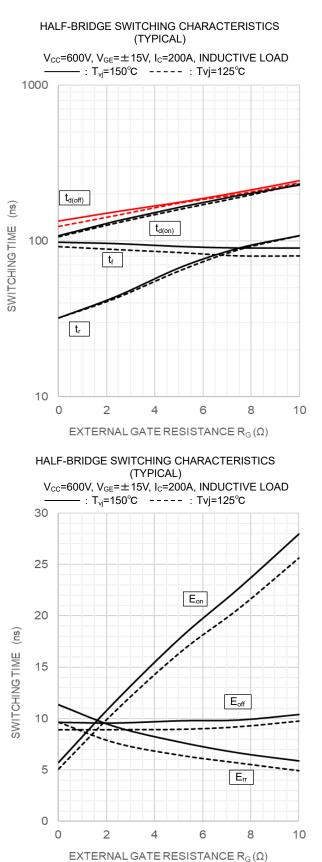
1

0

6

8





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100

200

COLLECTOR CURRENT I<sub>C</sub> (A)

300

0.0

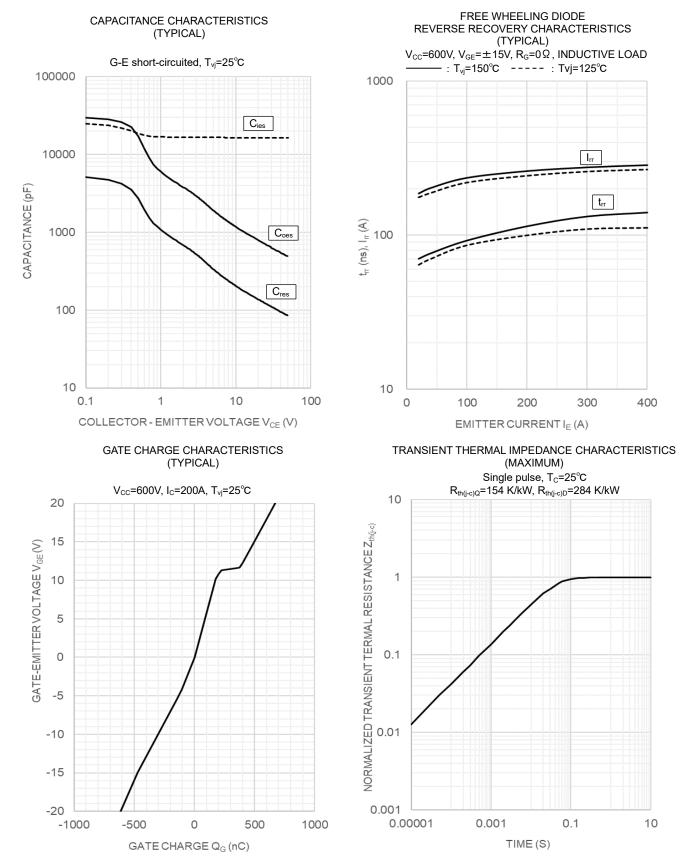
0

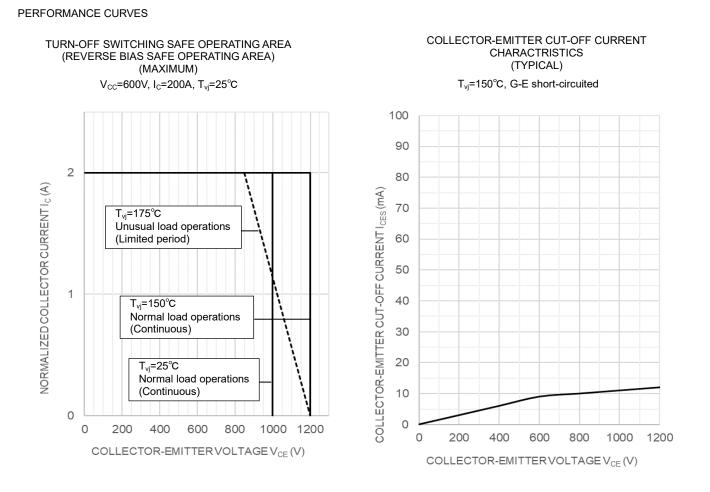
400

7

## <IGBT Modules> CM200DY-24TH HIGH POWER SWITCHING USE INSULATED TYPE

#### PERFORMANCE CURVES





Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

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